

74HC2G66-Q100; 74HCT2G66-Q100

Dual single-pole single-throw analog switch

Rev. 1 — 18 November 2013

Product data sheet

1. General description

The 74HC2G66-Q100; 74HCT2G66-Q100 is a dual single pole, single-throw analog switch. Each switch has two input/output terminals (nY and nZ) and a digital enable input (nE). When nE is LOW, the analog switch is turned off. Inputs include clamp diodes that enable the use of current limiting resistors to interface inputs to voltages in excess of V_{CC} .

This product has been qualified to the Automotive Electronics Council (AEC) standard Q100 (Grade 1) and is suitable for use in automotive applications.

2. Features and benefits

- Automotive product qualification in accordance with AEC-Q100 (Grade 1)
 - ◆ Specified from $-40\text{ }^{\circ}\text{C}$ to $+85\text{ }^{\circ}\text{C}$ and from $-40\text{ }^{\circ}\text{C}$ to $+125\text{ }^{\circ}\text{C}$
- Wide supply voltage range from 2.0 V to 10.0 V for 74HC2G66-Q100
- Very low ON resistance:
 - ◆ $41\text{ }\Omega$ (typ.) at $V_{CC} = 4.5\text{ V}$
 - ◆ $30\text{ }\Omega$ (typ.) at $V_{CC} = 6.0\text{ V}$
 - ◆ $21\text{ }\Omega$ (typ.) at $V_{CC} = 9.0\text{ V}$
- High noise immunity
- Low power dissipation
- 25 mA continuous switch current
- Multiple package options
- ESD protection:
 - ◆ MIL-STD-883, method 3015 exceeds 2000 V
 - ◆ HBM JESD22-A114F exceeds 2000 V
 - ◆ MM JESD22-A115-A exceeds 200 V ($C = 200\text{ pF}$, $R = 0\text{ }\Omega$)



3. Ordering information

Table 1. Ordering information

Type number	Package			
	Temperature range	Name	Description	Version
74HC2G66DP-Q100	−40 °C to +125 °C	TSSOP8	plastic thin shrink small outline package; 8 leads; body width 3 mm; lead length 0.5 mm	SOT505-2
74HCT2G66DP-Q100				
74HC2G66DC-Q100	−40 °C to +125 °C	VSSOP8	plastic very thin shrink small outline package; 8 leads; body width 2.3 mm	SOT765-1
74HCT2G66DC-Q100				

4. Marking

Table 2. Marking codes

Type number	Marking ^[1]
74HC2G66DP-Q100	H66
74HCT2G66DP-Q100	T66
74HC2G66DC-Q100	H66
74HCT2G66DC-Q100	T66

[1] The pin 1 indicator is located on the lower left corner of the device, below the marking code.

5. Functional diagram

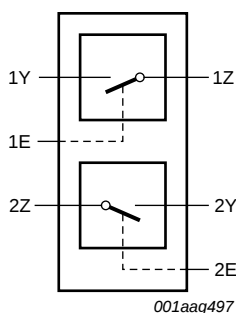


Fig 1. Logic symbol

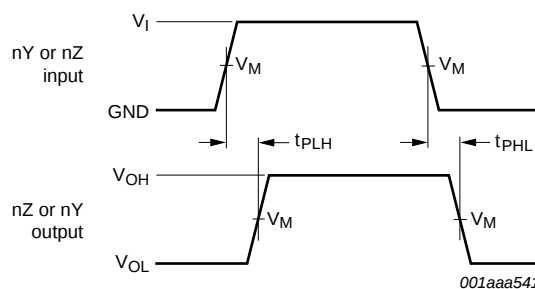


Fig 2. Logic diagram for 1 switch

6. Pinning information

6.1 Pinning

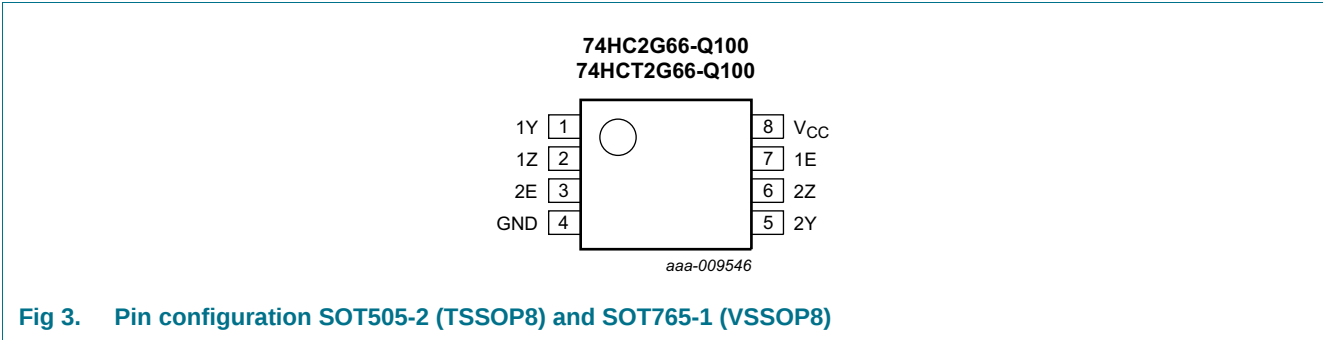


Fig 3. Pin configuration SOT505-2 (TSSOP8) and SOT765-1 (VSSOP8)

6.2 Pin description

Table 3. Pin description

Symbol	Pin	Description
1Y, 2Y	1, 5	independent input or output
1Z, 2Z	2, 6	independent input or output
GND	4	ground (0 V)
1E, 2E	7, 3	enable input (active HIGH)
V _{CC}	8	supply voltage

7. Functional description

Table 4. Function table^[1]

Input nE	Switch
L	OFF
H	ON

[1] H = HIGH voltage level; L = LOW voltage level.

8. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134). Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{CC}	supply voltage		-0.5	+11.0	V
I_{IK}	input clamping current	$V_I < -0.5\text{ V}$ or $V_I > V_{CC} + 0.5\text{ V}$	[1] -	± 20	mA
I_{SK}	switch clamping current	$V_I < -0.5\text{ V}$ or $V_I > V_{CC} + 0.5\text{ V}$	[1] -	± 20	mA
I_{SW}	switch current	$V_{SW} > -0.5\text{ V}$ or $V_{SW} < V_{CC} + 0.5\text{ V}$	-	± 20	mA
I_{CC}	supply current		-	30	mA
I_{GND}	ground current		-30	-	mA
T_{stg}	storage temperature		-65	+150	°C
P_{tot}	total power dissipation	$T_{amb} = -40\text{ °C}$ to $+125\text{ °C}$			
		per package	[2] -	300	mW
		per switch	[2] -	100	mW

[1] The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

[2] For TSSOP8 packages: above 55 °C the value of P_{tot} derates linearly with 2.5 mW/K.

For VSSOP8 packages: above 110 °C the value of P_{tot} derates linearly with 8.0 mW/K.

9. Recommended operating conditions

Table 6. Recommended operating conditions

Voltages are referenced to GND (ground = 0 V). [1]

Symbol	Parameter	Conditions	74HC2G66-Q100			74HCT2G66-Q100			Unit
			Min	Typ	Max	Min	Typ	Max	
V_{CC}	supply voltage		2.0	5.0	10.0	4.5	5.0	5.5	V
V_I	input voltage		0	-	V_{CC}	0	-	V_{CC}	V
V_O	output voltage		0	-	V_{CC}	0	-	V_{CC}	V
V_{SW}	switch voltage		0	-	V_{CC}	0	-	V_{CC}	V
T_{amb}	ambient temperature		-40	+25	+125	-40	+25	+125	°C
$\Delta t/\Delta V$	input transition rise and fall rate	$V_{CC} = 2.0\text{ V}$	-	-	625	-	-	-	ns/V
		$V_{CC} = 4.5\text{ V}$	-	1.67	139	-	1.67	139	ns/V
		$V_{CC} = 6.0\text{ V}$	-	-	83	-	-	-	ns/V
		$V_{CC} = 10.0\text{ V}$	-	-	35	-	-	-	ns/V

[1] To avoid drawing V_{CC} current out of pin nZ, when switch current flows in pin nY, the voltage drop across the bidirectional switch must not exceed 0.4 V. If the switch current flows into pin nZ, no V_{CC} current flows out of terminal nY. In this case, there is no limit for the voltage drop across the switch, but the voltage at pins nY and nZ may not exceed V_{CC} or GND.

10. Static characteristics

Table 7. Static characteristics

Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	–40 °C to +85 °C			–40 °C to +125 °C		Unit
			Min	Typ ^[1]	Max	Min	Max	
74HC2G66-Q100								
V _{IH}	HIGH-level input voltage	V _{CC} = 2.0 V	1.5	1.2	-	1.5	-	V
		V _{CC} = 4.5 V	3.15	2.4	-	3.15	-	V
		V _{CC} = 6.0 V	4.2	3.2	-	4.2	-	V
		V _{CC} = 9.0 V	6.3	4.7	-	6.3	-	V
V _{IL}	LOW-level input voltage	V _{CC} = 2.0 V	-	0.8	0.5	-	0.5	V
		V _{CC} = 4.5 V	-	2.1	1.35	-	1.35	V
		V _{CC} = 6.0 V	-	2.8	1.8	-	1.8	V
		V _{CC} = 9.0 V	-	4.3	2.7	-	2.7	V
I _I	input leakage current	nE; V _I = V _{CC} or GND						
		V _{CC} = 6.0 V	-	-	±0.1	-	±0.1	μA
		V _{CC} = 9.0 V	-	-	±0.2	-	±0.2	μA
I _{S(OFF)}	OFF-state leakage current	nY or nZ; V _{CC} = 9.0 V; see Figure 4	-	0.1	1.0	-	1.0	μA
I _{S(ON)}	ON-state leakage current	nY or nZ; V _{CC} = 9.0 V; see Figure 5	-	0.1	1.0	-	1.0	μA
I _{CC}	supply current	nE, nY and nZ = V _{CC} or GND						
		V _{CC} = 6.0 V	-	-	10	-	20	μA
		V _{CC} = 9.0 V	-	-	20	-	40	μA
C _I	input capacitance		-	3.5	-	-	-	pF
C _{PD}	power dissipation capacitance		-	9	-	-	-	pF
C _{S(ON)}	ON-state capacitance		-	8	-	-	-	pF
74HCT2G66-Q100								
V _{IH}	HIGH-level input voltage	V _{CC} = 4.5 V to 5.5 V	2.0	1.6	-	2.0	-	V
V _{IL}	LOW-level input voltage	V _{CC} = 4.5 V to 5.5 V	-	1.2	0.8	-	0.8	V
I _I	input leakage current	nE; V _I = V _{CC} or GND; V _{CC} = 5.5 V	-	-	±1.0	-	±1.0	μA
I _{S(OFF)}	OFF-state leakage current	nY or nZ; V _{CC} = 5.5 V; see Figure 4	-	0.1	1.0	-	1.0	μA
I _{S(ON)}	ON-state leakage current	nY or nZ; V _{CC} = 5.5 V; see Figure 5	-	0.1	1.0	-	1.0	μA
I _{CC}	supply current	nE, nY and nZ = V _{CC} or GND; V _{CC} = 4.5 V to 5.5 V	-	-	10	-	20	μA
ΔI _{CC}	additional supply current	nE = V _{CC} – 2.1 V; I _O = 0 A; V _{CC} = 4.5 V to 5.5 V;	-	-	375	-	410	μA

Table 7. Static characteristics ...continued
Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	-40 °C to +85 °C			-40 °C to +125 °C		Unit
			Min	Typ ^[1]	Max	Min	Max	
C _I	input capacitance		-	3.5	-	-	-	pF
C _{PD}	power dissipation capacitance		-	9	-	-	-	pF
C _{S(ON)}	ON-state capacitance		-	8	-	-	-	pF

[1] Typical values are measured at T_{amb} = 25 °C.

10.1 Test circuits

$V_I = V_{CC}$ or GND and $V_O =$ GND or V_{CC} .

Fig 4. Test circuit for measuring OFF-state leakage current

$V_I = V_{CC}$ or GND and $V_O =$ open circuit.

Fig 5. Test circuit for measuring ON-state leakage current

10.2 ON resistance

Table 8. ON resistance for 74HC2G66 and 74HCT2G66

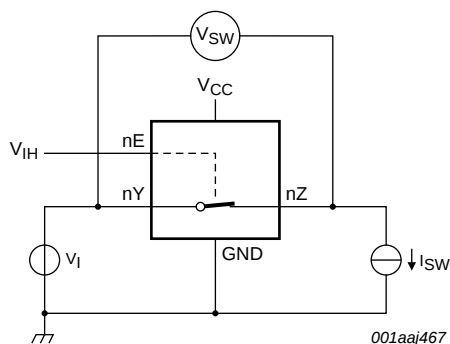
At recommended operating conditions; voltages are referenced to GND (ground 0 V); for graph see [Figure 7](#).

Symbol	Parameter	Conditions	–40 °C to +85 °C			–40 °C to +125 °C		Unit
			Min	Typ ^[2]	Max	Min	Max	
74HC2G66-Q100 ^[1]								
R _{ON(peak)}	ON resistance (peak)	V _I = GND to V _{CC} ; see Figure 6 and 7						
		I _{SW} = 0.1 mA; V _{CC} = 2.0 V	-	250	-	-	-	Ω
		I _{SW} = 1.0 mA; V _{CC} = 4.5 V	-	41	118	-	142	Ω
		I _{SW} = 1.0 mA; V _{CC} = 6.0 V	-	30	105	-	126	Ω
		I _{SW} = 1.0 mA; V _{CC} = 9.0 V	-	21	88	-	105	Ω
R _{ON(rail)}	ON resistance (rail)	V _I = GND; see Figure 6 and 7						
		I _{SW} = 0.1 mA; V _{CC} = 2.0 V	-	65	-	-	-	Ω
		I _{SW} = 1.0 mA; V _{CC} = 4.5 V	-	28	95	-	115	Ω
		I _{SW} = 1.0 mA; V _{CC} = 6.0 V	-	22	82	-	100	Ω
		I _{SW} = 1.0 mA; V _{CC} = 9.0 V	-	18	70	-	80	Ω
		V _I = V _{CC} ; see Figure 6 and 7						
		I _{SW} = 0.1 mA; V _{CC} = 2.0 V	-	65	-	-	-	Ω
		I _{SW} = 1.0 mA; V _{CC} = 4.5 V	-	31	106	-	128	Ω
		I _{SW} = 1.0 mA; V _{CC} = 6.0 V	-	23	94	-	113	Ω
		I _{SW} = 1.0 mA; V _{CC} = 9.0 V	-	19	78	-	95	Ω
ΔR _{ON}	ON resistance mismatch between channels	V _I = V _{CC} to GND; see Figure 6 and 7						
		V _{CC} = 4.5 V	-	5	-	-	-	Ω
		V _{CC} = 6.0 V	-	4	-	-	-	Ω
		V _{CC} = 9.0 V	-	3	-	-	-	Ω
74HCT2G66-Q100								
R _{ON(peak)}	ON resistance (peak)	V _I = GND to V _{CC} ; see Figure 6 and 7						
		I _{SW} = 1.0 mA; V _{CC} = 4.5 V	-	41	118	-	142	Ω
R _{ON(rail)}	ON resistance (rail)	V _I = GND; see Figure 6 and 7						
		I _{SW} = 1.0 mA; V _{CC} = 4.5 V	-	28	95	-	115	Ω
		V _I = V _{CC} ; see Figure 6 and 7						
		I _{SW} = 1.0 mA; V _{CC} = 4.5 V	-	31	106	-	128	Ω
ΔR _{ON}	ON resistance mismatch between channels	V _I = V _{CC} to GND; see Figure 6 and 7						
		V _{CC} = 4.5 V	-	5	-	-	-	Ω

[1] At supply voltages approaching 2 V, the ON resistance becomes extremely non-linear. Therefore it is recommended that these devices be used to transmit digital signals only, when using this supply voltage.

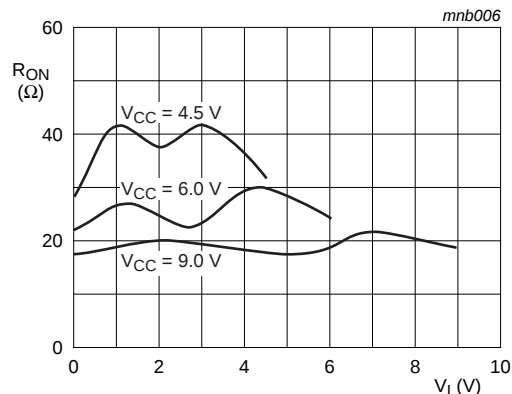
[2] Typical values are measured at T_{amb} = 25 °C.

10.3 ON resistance test circuit and graphs



$$R_{ON} = V_{SW} / I_{SW}$$

Fig 6. Test circuit for measuring ON resistance



$T_{amb} = 25\text{ }^{\circ}\text{C}$.

Fig 7. Typical ON resistance as a function of input voltage

11. Dynamic characteristics

Table 9. Dynamic characteristics

Voltages are referenced to GND (ground = 0 V); for test circuit, see [Figure 10](#).

Symbol	Parameter	Conditions	−40 °C to +85 °C			−40 °C to +125 °C		Unit
			Min	Typ ^[1]	Max	Min	Max	
74HC2G66-Q100								
t _{pd}	propagation delay	nY to nZ or nZ to nY; R _L = ∞ Ω; see Figure 8	[2]					
		V _{CC} = 2.0 V	-	6.5	65	-	80	ns
		V _{CC} = 4.5 V	-	2	13	-	15	ns
		V _{CC} = 6.0 V	-	1.5	11	-	14	ns
		V _{CC} = 9.0 V	-	1.2	10	-	12	ns
t _{en}	enable time	nE to nY or nZ; see Figure 9	[2]					
		V _{CC} = 2.0 V	-	40	125	-	150	ns
		V _{CC} = 4.5 V	-	12	29	-	30	ns
		V _{CC} = 6.0 V	-	10	21	-	26	ns
		V _{CC} = 9.0 V	-	7	16	-	20	ns
t _{dis}	disable time	nE to nY or nZ; see Figure 9	[2]					
		V _{CC} = 2.0 V	-	21	145	-	175	ns
		V _{CC} = 4.5 V	-	12	29	-	35	ns
		V _{CC} = 6.0 V	-	11	28	-	33	ns
		V _{CC} = 9.0 V	-	10	23	-	27	ns
C _{PD}	power dissipation capacitance	V _I = GND to V _{CC}	[3]	-	9	-	-	pF

Table 9. Dynamic characteristics ...continued

Voltages are referenced to GND (ground = 0 V); for test circuit, see [Figure 10](#).

Symbol	Parameter	Conditions	−40 °C to +85 °C			−40 °C to +125 °C		Unit
			Min	Typ ^[1]	Max	Min	Max	
74HCT2G66-Q100								
t _{pd}	propagation delay	nY to nZ or nZ to nY; R _L = ∞ Ω; see Figure 8	[2]					
		V _{CC} = 4.5 V	-	2	15	-	18	ns
t _{en}	enable time	nE to nY or nZ; see Figure 9	[2]					
		V _{CC} = 4.5 V	-	13	30	-	36	ns
t _{dis}	disable time	nE to nY or nZ; see Figure 9	[2]					
		V _{CC} = 4.5 V	-	13	44	-	53	ns
C _{PD}	power dissipation capacitance	V _I = GND to V _{CC} − 1.5 V	[3]	-	9	-	-	pF

[1] All typical values are measured at $T_{amb} = 25 \text{ °C}$.

[2] t_{pd} is the same as t_{PLH} and t_{PHL} .

t_{en} is the same as t_{PZL} and t_{PZH} .

t_{dis} is the same as t_{PLZ} and t_{PHZ} .

[3] C_{PD} is used to determine the dynamic power dissipation P_D (μW).

$P_D = C_{PD} \times V_{CC}^2 \times f_i + \Sigma((C_L \times C_{SW}) \times V_{CC}^2 \times f_o)$ where:

f_i = input frequency in MHz;

f_o = output frequency in MHz;

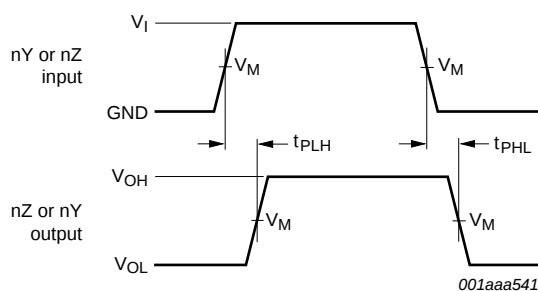
C_L = output load capacitance in pF;

C_{SW} = maximum switch capacitance in pF (see [Table 7](#));

V_{CC} = supply voltage in volts;

$\Sigma((C_L \times C_{SW}) \times V_{CC}^2 \times f_o)$ = sum of outputs.

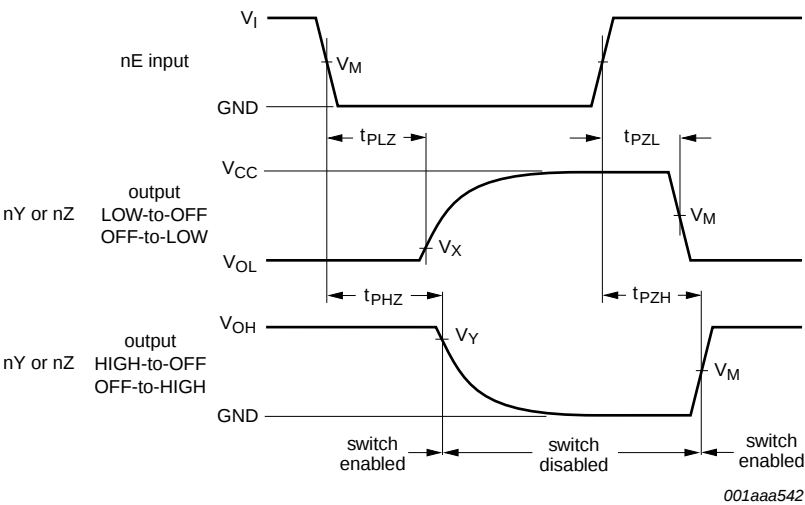
11.1 Waveforms and test circuit



Measurement points are given in [Table 10](#).

Logic levels: V_{OL} and V_{OH} are typical output voltage levels that occur with the output load.

Fig 8. Input (nY or nZ) to output (nZ or nY) propagation delays



Measurement points are given in [Table 10](#).
Logic levels: V_{OL} and V_{OH} are typical output voltage levels that occur with the output load.

Fig 9. Enable and disable times

Table 10. Measurement points

Type	Input	Output		
	V_M	V_M	V_X	V_Y
74HC2G66-Q100	$0.5V_{CC}$	$0.5V_{CC}$	$V_{OL} + 10\%$	$V_{OH} - 10\%$
74HCT2G66-Q100	1.3 V	1.3 V	$V_{OL} + 10\%$	$V_{OH} - 10\%$

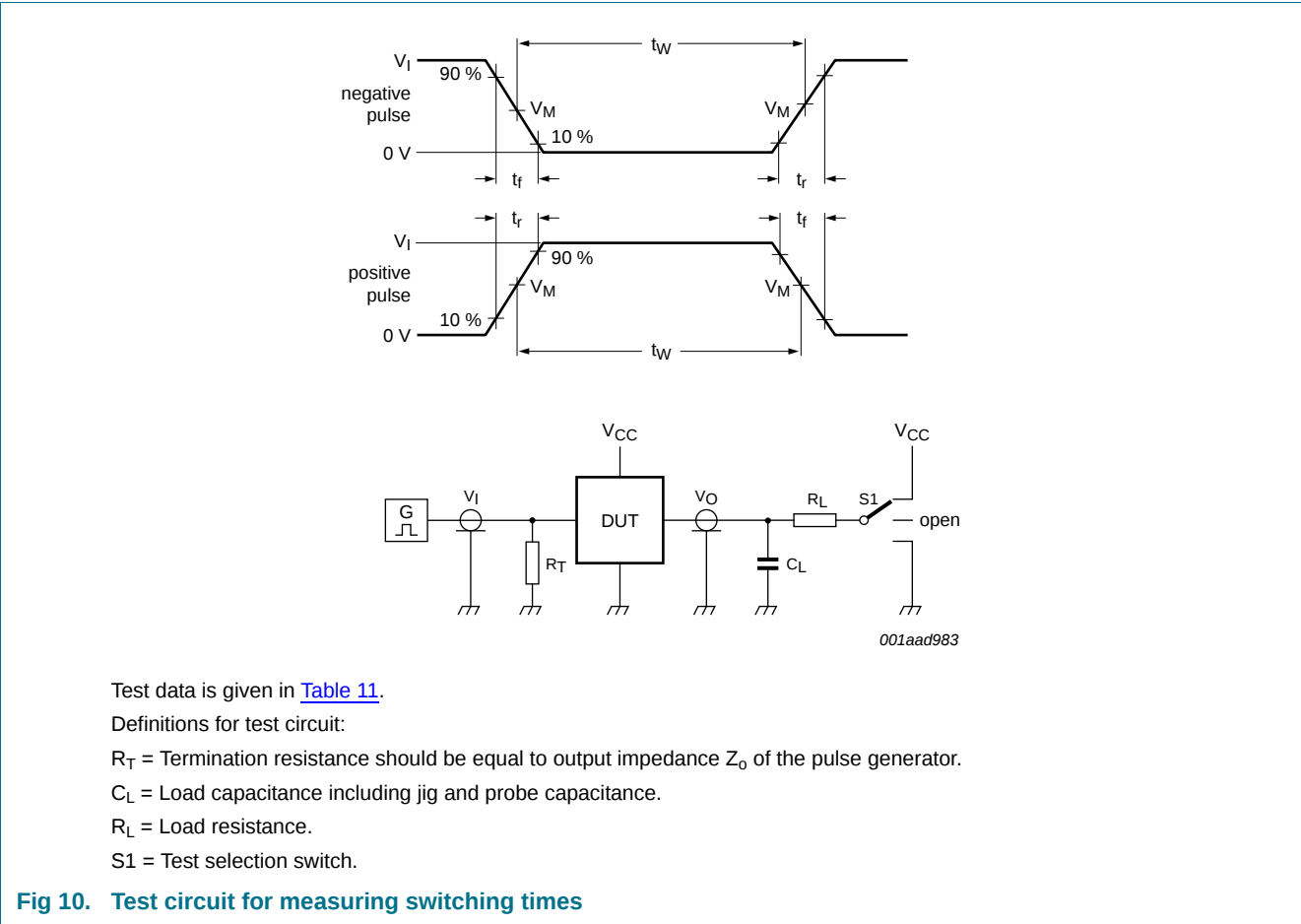


Table 11. Test data

Type	Input		Load		S1 position		
	V_I	t_r, t_f ^[1]	C_L	R_L	t_{PHL}, t_{PLH}	t_{PZH}, t_{PHZ}	t_{PZL}, t_{PLZ}
74HC2G66-Q100	GND to V_{CC}	6 ns	50 pF	1 k Ω	open	GND	V_{CC}
74HCT2G66-Q100	GND to 3 V	6 ns	50 pF	1 k Ω	open	GND	V_{CC}

[1] There is no constraint on t_r, t_f with a 50 % duty factor when measuring f_{max} .

11.2 Additional dynamic characteristics

Table 12. Additional dynamic characteristics for 74HC2G66 and 74HCT2G66

$GND = 0\text{ V}$; $t_r = t_f = 6.0\text{ ns}$; $C_L = 50\text{ pF}$; unless otherwise specified. All typical values are measured at $T_{amb} = 25\text{ }^{\circ}\text{C}$.

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
THD	total harmonic distortion	$f_i = 1\text{ kHz}$; $R_L = 10\text{ k}\Omega$; see Figure 11				%
		$V_{CC} = 4.5\text{ V}$; $V_I = 4.0\text{ V (p-p)}$	-	0.04	-	%
		$V_{CC} = 9.0\text{ V}$; $V_I = 8.0\text{ V (p-p)}$	-	0.02	-	%
		$f_i = 10\text{ kHz}$; $R_L = 10\text{ k}\Omega$; see Figure 11				
		$V_{CC} = 4.5\text{ V}$; $V_I = 4.0\text{ V (p-p)}$	-	0.12	-	%
		$V_{CC} = 9.0\text{ V}$; $V_I = 8.0\text{ V (p-p)}$	-	0.06	-	%
$f_{(-3\text{dB})}$	–3 dB frequency response	$R_L = 50\text{ }\Omega$; $C_L = 10\text{ pF}$; see Figure 12 and 13				
		$V_{CC} = 4.5\text{ V}$	-	180	-	MHz
		$V_{CC} = 9.0\text{ V}$	-	200	-	MHz
α_{iso}	isolation (OFF-state)	$R_L = 600\text{ }\Omega$; $f_i = 1\text{ MHz}$; see Figure 14 and 15				
		$V_{CC} = 4.5\text{ V}$	-	–50	-	dB
		$V_{CC} = 9.0\text{ V}$	-	–50	-	dB
V_{ct}	crosstalk voltage	between digital input and switch (peak to peak value); $R_L = 600\text{ }\Omega$; $f_i = 1\text{ MHz}$; see Figure 16				
		$V_{CC} = 4.5\text{ V}$	-	110	-	mV
		$V_{CC} = 9.0\text{ V}$	-	220	-	mV
Xtalk	crosstalk	between switches; $R_L = 600\text{ }\Omega$; $f_i = 1\text{ MHz}$; see Figure 17				
		$V_{CC} = 4.5\text{ V}$	-	–60	-	dB
		$V_{CC} = 9.0\text{ V}$	-	–60	-	dB

11.3 Test circuits and graphs

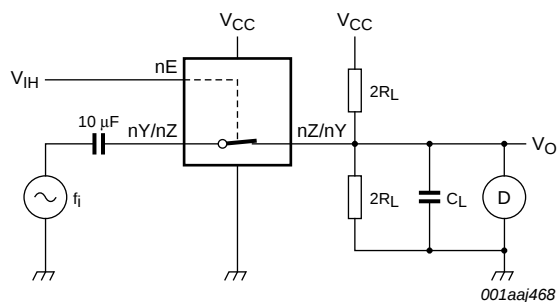
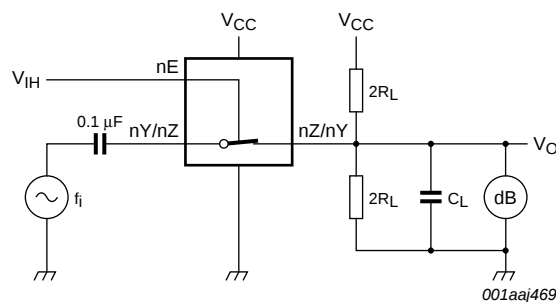
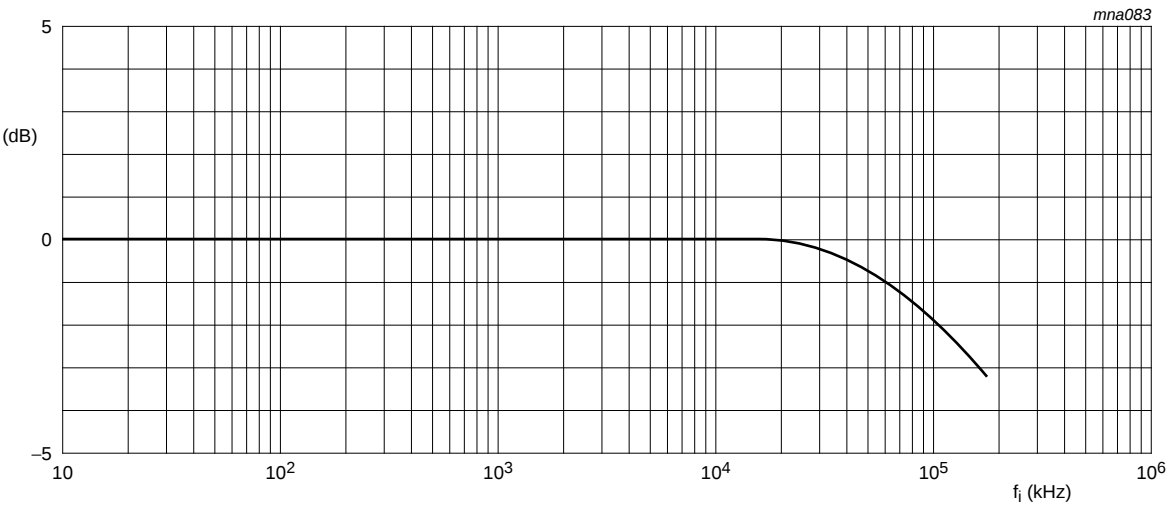


Fig 11. Test circuit for measuring total harmonic distortion



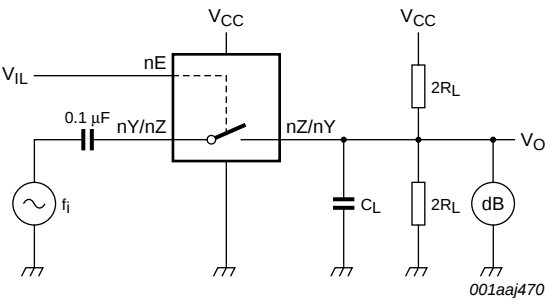
With $f_i = 1\text{ MHz}$, adjust the switch input voltage for a 0 dBm level at the switch output (0 dBm = 1 mW into 50 Ω). Then increase the input frequency until the dB meter reads –3 dB.

Fig 12. Test circuit for measuring the –3 dB frequency response



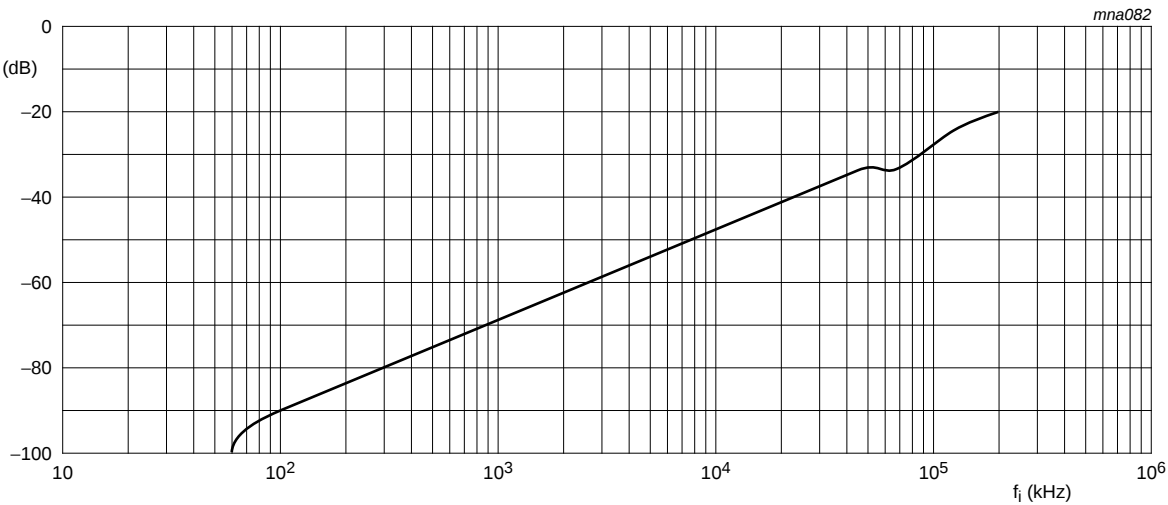
Test conditions: $V_{CC} = 4.5\text{ V}$; $GND = 0\text{ V}$; $R_L = 50\text{ }\Omega$; $R_{SOURCE} = 1\text{ k}\Omega$.

Fig 13. Typical -3 dB frequency response



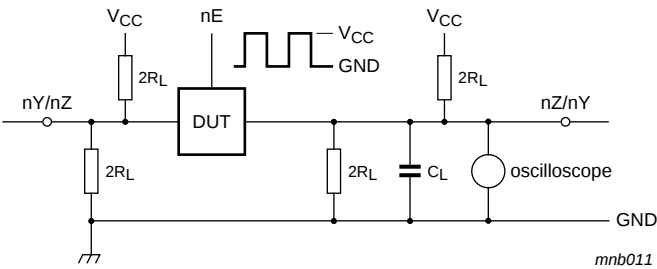
Adjust the switch input voltage for a 0 dBm level (0 dBm = 1 mW into 600 Ω)

Fig 14. Test circuit for measuring isolation (OFF-state)

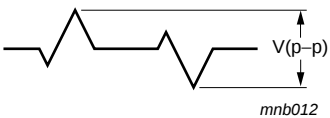


Test conditions: $V_{CC} = 4.5\text{ V}$; $GND = 0\text{ V}$; $R_L = 50\text{ }\Omega$; $R_{SOURCE} = 1\text{ k}\Omega$.

Fig 15. Typical isolation (OFF-state) as a function of frequency



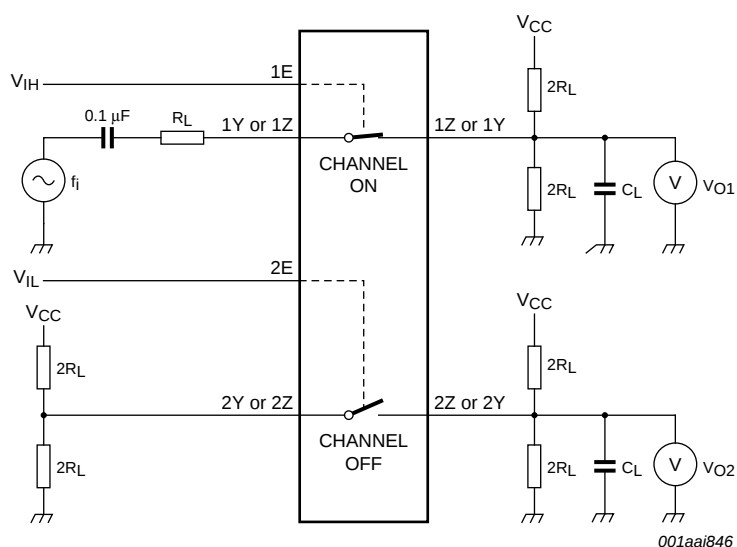
a. Circuit



b. Crosstalk voltage

Adjust the switch input voltage for a 0 dBm level (0 dBm = 1 mW into 600 Ω)

Fig 16. Test circuit for measuring crosstalk voltage (between the digital input and the switch)



001aa1846

Adjust the switch input voltage for a 0 dBm level (0 dBm = 1 mW into 600 Ω)

Fig 17. Test circuit for measuring crosstalk (between the switches)

12. Package outline

TSSOP8: plastic thin shrink small outline package; 8 leads; body width 3 mm; lead length 0.5 mm SOT505-2

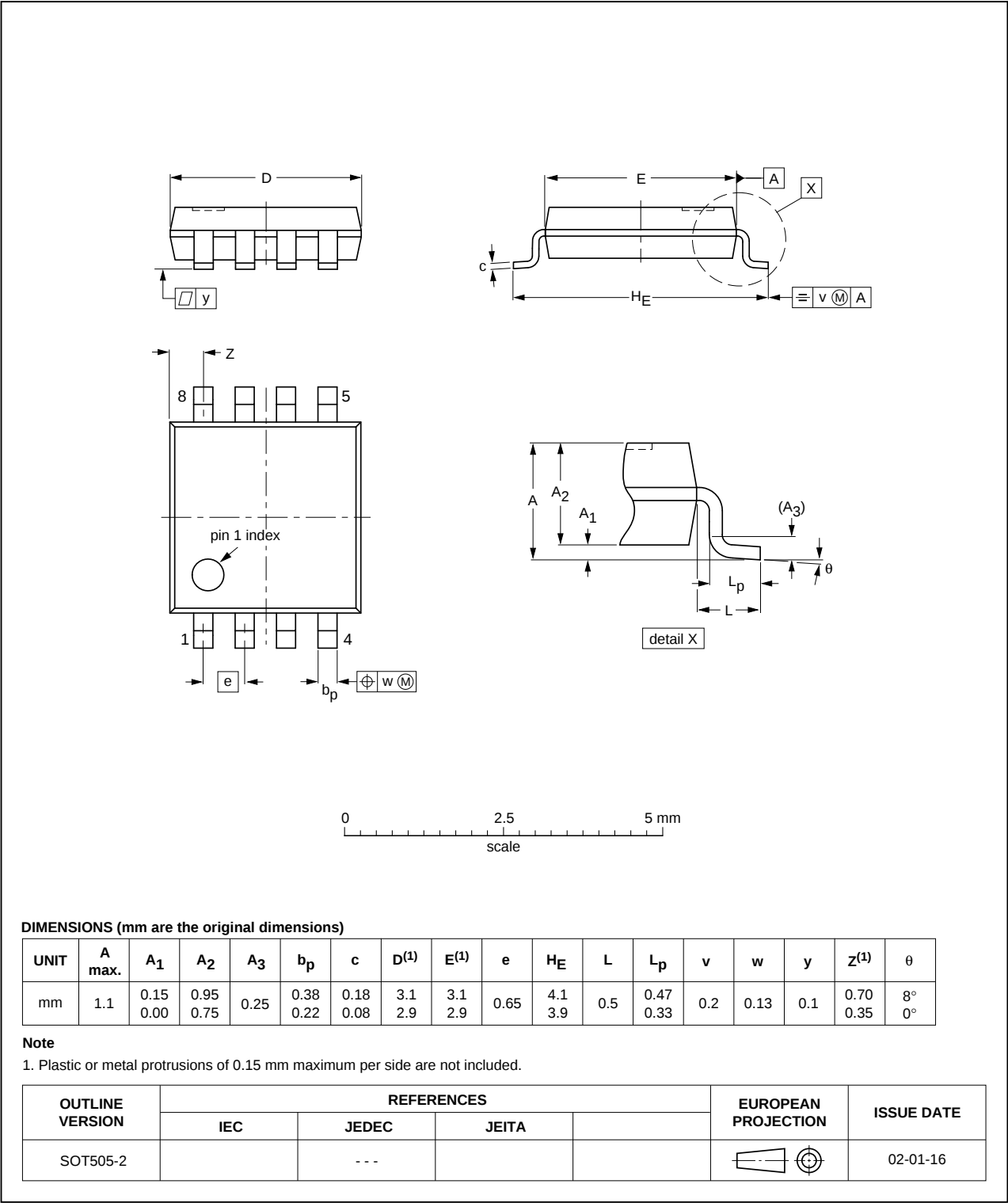


Fig 18. Package outline SOT505-2 (TSSOP8)

VSSOP8: plastic very thin shrink small outline package; 8 leads; body width 2.3 mm

SOT765-1

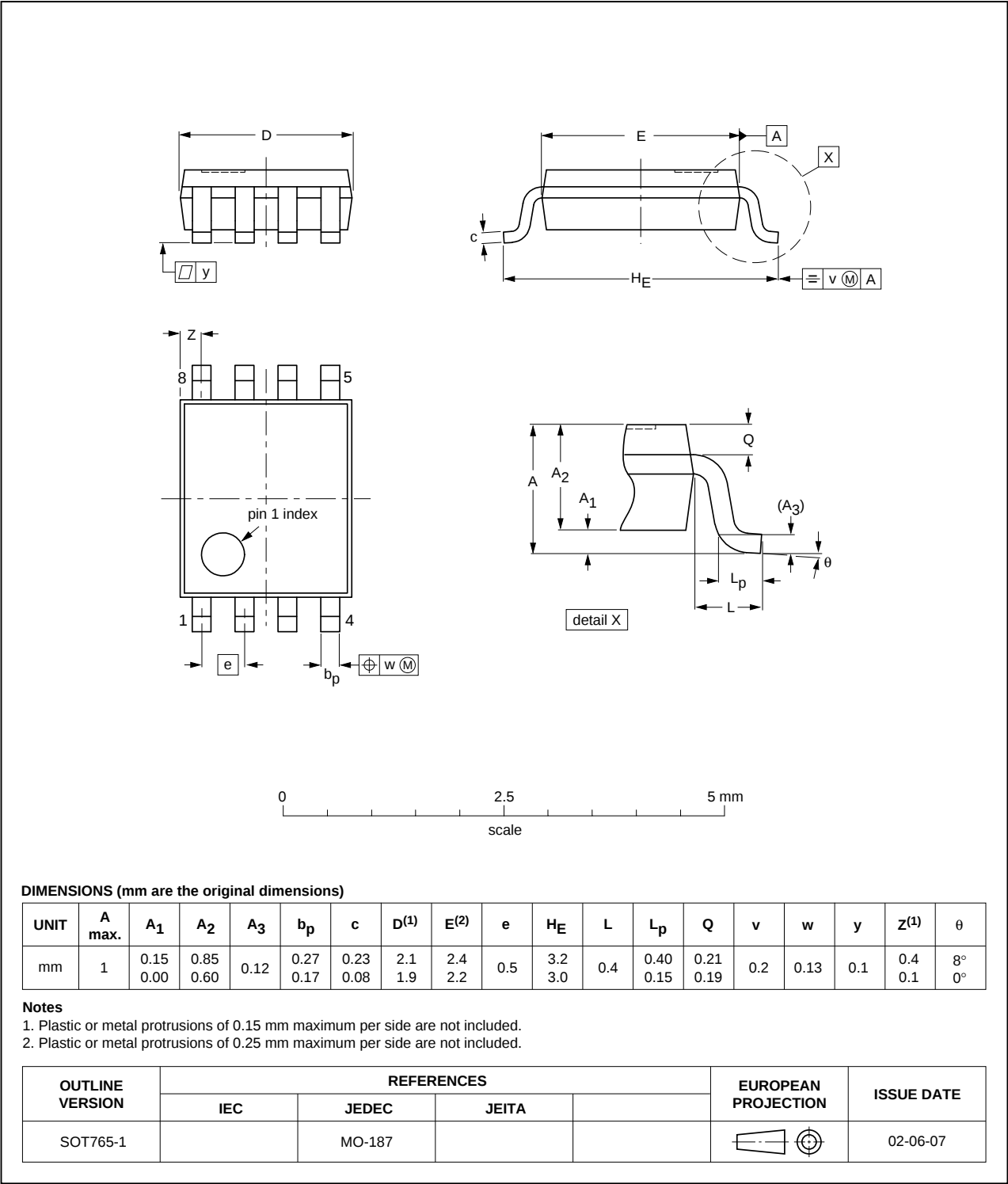


Fig 19. Package outline SOT765-1 (VSSOP8)

13. Abbreviations

Table 13. Abbreviations

Acronym	Description
CMOS	Complementary Metal-Oxide Semiconductor
ESD	ElectroStatic Discharge
HBM	Human Body Model
MIL	Military
MM	Machine Model
DUT	Device Under Test

14. Revision history

Table 14. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
74HC_HCT2G66_Q100 v.1	20131118	Product data sheet	-	-

15. Legal information

15.1 Data sheet status

Document status ^{[1][2]}	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

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Date of release: 18 November 2013

Document identifier: 74HC_HCT2G66_Q100